

Abstract of the Disclosure:

A semiconductor module has a plurality of contact terminals used for external data interchange, address interchange and/or command interchange during normal operation of the

5 semiconductor module. The module further has at least one further contact terminal that is not used for external data interchange, address interchange and/or command interchange during normal operation. A mode of operation for ascertaining and outputting test information and, respectively, for

10 configuring the semiconductor module during normal operation of the semiconductor module is initialized and set via a test and configuration circuit, which is connected to the further contact terminal, with data interchange, address interchange and/or command interchange simultaneously being effected

15 during normal operation of the semiconductor module via the contact terminals. This provides a semiconductor module, which makes it possible to carry out a functional test or a configuration in proximity to the application even during normal operation of the module in the application.

REL/nt